

**STATEMENT UNDER 37 CFR 1.97(e) ACCOMPANYING
INFORMATION DISCLOSURE STATEMENT**

Docket No.
14846-36

In Re Application Of: **Aura Yanavi**

Serial No.
TBD

Filing Date
November 20, 2003

Examiner
TBD

Group Art Unit
TBD

Invention: **Methods and Systems For Predicting Software Defects In An Upcoming Software Release**

TO THE COMMISSIONER FOR PATENTS:

This is a statement under the provisions of 37 CFR 1.97(e) in the above-identified application.

Check applicable statement herebelow:

Statement Under 37 CFR 1.97(e)(1)

- ☐ Each item of information contained in the accompanying Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Information Disclosure Statement.

Statement Under 37 CFR 1.97(e)(2)

- ☒ No item of information contained in the accompanying Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the undersigned person, after making reasonable inquiry, no item of information contained in the accompanying Information Disclosure Statement was known to any individual designated in 37 CFR 1.56(c) more than three months prior to the filing of the Information Disclosure Statement.


Signature

Dated: **November 20, 2003**

**George Morgan, (Reg. No. 46,505)
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Signature of Person Mailing Correspondence

Kelly Billingsley

Typed or Printed Name of Person Mailing Correspondence

cc:

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. 14846-36	SERIAL NO. TBA
	Methods and Systems For Predicting Software Defects.....	
	FILING November 20, 2003	GROUP TBA

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	US 6,073,107	06/06/00	Minkiewicz et al.			
	US 6,477,471	11/05/02	Hedstrom et al.			
	US 6,546,506	04/08/03	Lewis			
	US 5,446,895	08/29/95	White et al.			
	US 5,655,074	08/05/97	Rauscher			
	US 5,758,061	05/26/98	Plum			
	US 5,903,897	05/11/99	Carrier III et al.			
	US 5,960,196	09/28/99	Carrier III et al.			
	US 6,363,524	03/26/02	Loy			
	US 6,405,364	06/11/02	Bowman-Amuah			
	US 6,513,154	01/28/03	Porterfield			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

		Hudepohl, J.P., et al., "Integrating Metrics and Models For Software Risk Assessment," p. 93, The Seventh International Symposium on Software Reliability Engineering (ISSRE'96) October 30-November 02, 1996, White Plains, NY (Abstract)
		Levendel, Y., "Reliability Analysis of Large Software Systems: Defect Data Modeling," pp. 141-152, IEEE Transactions on Software Engineering (Abstract)

EXAMINER	DATE CONSIDERED
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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				Methods and Systems For Predicting Software Defects.....			
				FILING November 20, 2003		GROUP TBA	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		US 6,519,763	02/11/03	Kaufer et al.			
		US 6,601,017	07/29/03	Kennedy et al.			
		US 6,601,018	07/29/03	Logan			
		US 6,601,233	07/29/03	Underwood			
		US 6,626,953	09/30/03	Johndrew et al.			
		US 6,629,266	09/30/03	Harper et al.			
		US 2002/0147961	10/10/02	Charters et al.			
		US 2002/0162090	10/31/02	Parnell et al.			
		US 2003/0018952	01/23/03	Roetzheim			
		US 2003/0033586	02/13/03	Lawler			
		US 2003/0188290	10/02/03	Corral			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
			Yu, T.J., et al., "An Analysis of Several Software Defect Models," pp. 1261-1270, IEEE Transactions on Software Engineering (Abstract)				
			Wohlin, C., et al., "Understanding the Sources of Software Defects: A Filtering Apporach,,: 8th International Workshop on Program Comprehension (IWPC'00), June 10-11, 2000 (Abstract)				
EXAMINER				DATE CONSIDERED			

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